



Beam test of thin epitaxial silicon strip sensors for the CMS phase II pixel upgrade

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Content



Motivation

Test beam setup

Analysis cuts and definitions

Charge collection

Noise

Conclusions





Test beam of thin epitaxial strip sensors to determine material characteristics







- Epitaxial silicon strips of n and p type (p-spray and p-stop isolation)
 - Baby additional from HPK campaign
- 100 µm thickness
- 80 µm pitch
- Irradiation with 800 MeV and 23 GeV protons
- Fluences up to 1.3 x $10^{16} n_{eq} \text{ cm}^{-2}$
- A few other sensors with 200 µm thickness



Strips detectors:

- Irradiation of sensor without readout electronics
- Higher noise → hit reconstruction using beam telescope

Unbiased charge collection measurement (no threshold involved)



Fake rejection

64 AC coupled strips



The EPIc test beam II



Beam generation at DESY test beam:

- Bremsstrahlung on C fiber
- Conversion in e⁺e⁻ on a metal target
- Momentum selection using a magnet
- Collimator to define the beam







- Beam telescope to reconstruct tracks
 - DATURA and ACONITE
 - AIDA pixel telescopes
- Trigger scintillators to define events
- Cooling for irradiated samples down to -27 C
- Moving stage for different incidence angles
- Minimize material in the beam





Setup I

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Setup II



Mother board





Readout system:

UH

- AliBaVa (<u>A Li</u>verpool <u>Ba</u>rcelona <u>Va</u>lencia) readout system: mother + daughter boards
- Readout of positive and negative signals
- Based on LHCb strip readout chip
- Triggered readout
- Analog pulse height for 2 x 128 channels
- Maximum event rate ~150 Hz



IV characteristic







Signal definition







10

2

SNR

Alignment





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Hit selection



Problem:

- Telescope integration time: ~ 150 µs
 ALiBaVa integration time: 25 ns

Many tracks on the telescope, (most probably) one on the strip sensor

Strategy:

The track with the highest charge deposit is the one that passed the strip at the right time \rightarrow Geometry cuts to evaluate all the tracks in one event

> Charge definition: Sum of the signal over 5 strips, centered on the hit one



Fig. from T. Mäenpää et al, Track-induced Clustering in Position Sensitive Detector Characterization IEEE 2009

Geometry cuts



-20 C

Epi100P, 23 GeV p, 3 x 10^{15} n_{eq} cm⁻², -800V,



UH

iii



Time cut





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Charge collection



Landau MPV [ADC]



Fitted Landau MPV in the time cut

Test beam data are in agreement with TCT measurements of diodes

Both show charge multiplication

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0.4

0.2

200

400

voltage [V]

1000

800

.3e16 cn

600



Noise

CCKS of the second seco

Signal not associated to a track





Signal-to-noise ratio





SNR \rightarrow ratio of Landau MPV and noise level

P-bulk strips:SNR close to pre-irradiation levels

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Micro discharges



Signal determination for **n-bulk** sensors is hard due to micro discharges

- \rightarrow problems in the alignment (trustworthy hits to be defined)
- \rightarrow difficult common mode estimation

 \rightarrow more cuts can improve the situation



See talk from A. Nürnberg at the 23rd RD50 workshop



Conclusions and outlook



Conclusions:

- First test beam with highly irradiated epitaxial strip sensors
- Developed tools to analyze telescope and ALiBaVa data
- P-bulk
 - Small degradation of charge collection up to $\Phi_{eq} = 3 \times 10^{15} \text{ cm}^{-2}$
 - Noise compatible with non irradiated device
 - SNR close to pre-irradiation levels
- Charge multiplication confirmed by CCE measurement of diodes
- Irradiated n-bulk sensors show micro discharges

Outlook:

- Improve the alignment procedure
- Include the highest irradiation in the analysis
- Improve n-bulk sensors analysis
- Use the calibration runs to get rid of inhomogeneities / temperature effects



TB summary table



Taken data 🛛 🛄 Used in the talk

	Sensor	0 P	1.5e15 P	1.5e15 N	0 N (70um)	3e15 P	3e15 N	1.5e15 Y	1.3e16 P	1.3e16 Y	0 Y	1e15 800M P	1e15 800M N	1e15 800M Y	N70	1.3e16 N	E16	FTH200Y E16	MCZ200N E16	MCZ200Y E16
Angle	Voltage	Beam 0 / 1	Beam 1	Beam 1	Beam 1	Ream 2	Beam 2	Beam 2	Beam 2	Beam 2/3	Beam 3	Beam 4	Beam 4	Beam 4	Beam 4	Beam 4	Beam 5	Beam 5	Beam 5	Beam 5
0	1000	skipped	done	skipped	skipped	done	skipped	done	skipped	skipped	skipped	done	skipped	done	skipped	skipped	done	skipped	done (900)	done
0	800	skipped	done	skipped	skipped	skipped	skipped	done	done	done	skipped	done	done / 700V	done	skipped	done / 700V	done	skipped	done	done
0	600	skipped	done	skipped	skipped	done	done	done	done	done	done	done	done / 650V	done	skipped	done	done	done	done	done
0	500	skipped	done	done	skipped	skipped	done	skipped	skipped	skipped	skipped	skipped	done	skipped	skipped	skipped	skipped	skipped	skipped	skipped
0	400	done	done	done	done	done	done	done	done	done	done	done	done	done	skipped	done	done	done	done	done
0	300	done	done	done	done	skipped	done	skipped	skipped	skipped	skipped	skipped	skipped	skipped	skipped	done	skipped	skipped	skipped	skipped
0	200	done	done	done	skipped	done	done	done	done	done	done	done	done	done	done	done	skipped	skipped	skipped	skipped
0	100	done	done	done	done	skipped	done	done	done	skipped	done	skipped	skipped	skipped	done	done	skipped	skipped	skipped	skipped
25	1000	skipped	skipped	skipped	skipped	done	skipped	done	skipped	skipped	skipped	done	skipped	done	skipped	skipped	done	skipped	done (900)	done
25	800	skipped	skipped	skipped	skipped	done	skipped	done	done	done	skipped	done	skipped	done	skipped	skipped	done	skipped	done	done
25	600	skipped	skipped	skipped	skipped	done	done	done	done	done	skipped	done	skipped	done	skipped	done	done	done	done	done
25	400	skipped	skipped	skipped	skipped	skipped	skipped	skipped	skipped	skipped	done	skipped	done	skipped	skipped	skipped	done	done	done	done
25	300	done	done	done	done	done	done	done	done	skipped	skipped	done	done	done	skipped	done	skipped	skipped	skipped	skipped
25	200	skipped	skipped	skipped	skipped	skipped	skipped	skipped	skipped	skipped	skipped	skipped	done	skipped	done	skipped	skipped	skipped	skipped	skipped
51	100	done	done	done	done	skipped	done	skipped	skipped	skipped	skipped	skipped	skipped	skipped	done	done	-	-	skipped	skipped
51	1000	skipped	skipped	skipped	skipped	done	skipped	done	skipped	skipped	skipped	done	skipped	done	skipped	skipped	-		-	-
51	800	skipped	done	skipped	skipped	done	skipped	done	done	done	skipped	done	skipped	done	skipped	skipped	-	-	-	-
51	600	skipped	done	done	skipped	done	done	done	done	done	done	done	done / 650 V	done	skipped	done	-	-	-	-
51	500	skipped	skipped	skipped	done	skipped	skipped	skipped	skipped	skipped	skipped	skipped	skipped	skipped	skipped	skipped	-	-	-	121
51	400	done	done	done	skipped	done	done	done	done	done	done	done	done	done	skipped	done	-	-	-	-
51	300	done	done	done	done	skipped	done	skipped	skipped	skipped	skipped	skipped	done	skipped	skipped	skipped	100		5	10.75
51	200	done	skipped	skipped	skipped	done	done	done	done	skipped	done	done	done	done	done	done	1.0		-	0.70
51	100	done	done	done	done	skipped	done	done	skipped	skipped	done	skipped	skipped	skipped	done	done	-			-
31.7	1000	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	done		done (900)	done
31.7	800		-	-	-	-	-	-	-	-	-	-	-	-	-	-	done	-	done	done
31.7	600	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	done	done	done	done
31.7	400				-	-	-	-	-	-	-	-	-	1 - 1	-	-	done	done	done	done
36.8	1000	-	done	-	-	-	-	-	-	-	-	-	-	-	2	-	-	-	-	-
36.8	800		done		1.5	-	5		1070	-	5	5	1.5	-		1.5	(77)		5	1.7
36.8	600		done	-	1.5		-		1.70	1.0	-	-	-	1.53			-	-	2	0.50
36.8	400	-	250000 Events	-	-		-	-	-	-	-	-	-	(m)	-	1.0	-	-	-	1.00

Much analysis to be done, stay tuned!





Special thanks to:

- Test beam shifters
- HIWI students for the TCT measurements

Thank you for your attention





Backup



Oxygen content







Pedestal run analysis I







Pedestal run analysis II



Common mode \rightarrow all channels are shifted from their base line (event-wise)





For this bias, pedestal and noise levels similar to unirradiated sensor

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